## Technical Specifications of Chemical Phase analysis by Compact XRD

## 1.0 Bidder Eligibility Criteria-I

| Sl.<br>No | Bidder Eligibility Criteria-I   | Complied / Not Complied | Reference<br>Page No. | Remarks,<br>If any |
|-----------|---|-------------------------|-----------------------|--------------------|
| 1         | The bidder/OEM should have supplied at least 10 or more installations of the system or similar items of same make to IITs, NITs, IISERs, CSIR Labs or other Govt. R&D organizations in the last 7 years, PO copies or installation certificates along with contact details of end user need to be submitted as the proof of supply. IIT Madras reserves its right to verify the claims submitted by the bidder and the feedback from the previous customers will be part of technical evaluation. |                         |                       |                    |
| 3         | The bidder should clearly mention about their service set up in India (preferably in South part of India) for prompt service support along with contact details of service engineers specially trained on the offered system. Service should be provided within 48 hrs from the report of technical problem so that machine down time is minimized.  In case the Equipment / System remains non-operational for more than 5 days then warranty period will be extended for the                    |                         |                       |                    |
|           | equivalent period for which Equipment / System remained non-operational. Warranty extension in such case shall be done without prejudice to any other Term & condition of the contract.   |                         |                       |                    |

## 2.0 Technical Specifications II

Specifications for "Chemical Phase analysis by Compact XRD"

Compact Benchtop X-ray analyzer for phase identification and phase quantification of various samples along with capability for In-operando analysis of Coin Cells, Pouch Cell with facility for mounting electro chemical cell with Z height adjustment stage. The system should also have present & future upgrade capability for mounting non-ambient temperature dependent studies stage, 2D detector etc. The instrument specifications as outlined below.

## **Basic System Configuration:**

| Sl.<br>NO | SPECIFICATIONS               |   | Complied / Not Complied | Reference<br>,<br>Page. No. |  |  |  |
|-----------|------------------------------|---|-------------------------|-----------------------------|--|--|--|
| X-ray (   | X-ray Generator & X-ray Tube |   |                         |                             |  |  |  |
|           | Continuous                   |   |                         |                             |  |  |  |
| 1.        | rated<br>output              | 600W or higher  |                         |                             |  |  |  |
| 2.        | Voltage                      | 40.0 kV or higher   |                         |                             |  |  |  |
| 3.        | Current                      | 15.0 mA or higher   |                         |                             |  |  |  |
| 4.        |                              | HT Stability better than +/-0.01% for Mains stability +/- 10 %. |                         |                             |  |  |  |
| 5.        |                              | Fine Focus Cu Anode X-ray tube.                                 |                         |                             |  |  |  |

| 6.     |                              | Tube cooling internal. No external chiller Should be required  |  |
|--------|------------------------------|--|--|
| Gonion | ieter                        |  |  |
| 7.     |                              | High Precision, vertical type  |  |
| 8.     |                              | Goniometer with theta - theta OR theta-2theta Geometry   |  |
| 9.     | Range                        | -2° to 142° 2Theta or better   |  |
| 10.    | Radius                       | 145 mm or more   |  |
| 11.    | Scanning<br>Speed            | 0.01 ~ 100 degree/min or better  |  |
| 12.    | Minimum<br>Scanning<br>speed | 100deg/min or better   |  |
| 13.    | Minimum<br>Step Size         | Minimum Step Size: 0.001 deg or better   |  |
| Optics |                              |  |  |
| 14.    |                              | Necessary incident beam slits and soller slits should be provided.  The slits facilitate low angle diffraction typically from 1 deg onwards (total 3 nos.) |  |
| 15.    |                              | Necessary diffracted beam slits and soller slits should be provided  |  |
| 16.    |                              | Suitable Ni k-beta filter should be provided.  |  |
| 17.    |                              | Achievable resolution < 0.04° 2theta with NIST SRM LaB6.   |  |
| 18.    |                              | Linearity <0.04° 2theta with NIST SRM Si/Quartz/Al2O3  |  |
| 19.    |                              | Beam Knife should be offered.  |  |
| Sample | stage                        |  |  |
| 20.    | suge .                       | Sample stage with spinning capability to improve particle statistics and remove preferred orientation issues.  |  |
| 21.    |                              | Sample stage to mount coin cell (CR2032/CR2025/CR2016) for in-operando studies should be provided  |  |
| 22.    |                              | Stage with adjustable z-axis for mount thin pouch cell of 0.5 mm or less for in-operando studies should be provided.                                       |  |
| Sample | Holders                      |  |  |
| 23.    | Holders                      | Sample Holder for Spinner Sample Stage to hold powder for Reflection Geometry – Minimum 3pcs   |  |
| 24.    |                              | Air-Tight Sample holder for Spinning Sample stage to mount air sensitive sample in glove box and analysis in XRD should be provided                        |  |
| 25.    |                              | Minimum 2 no's of Zero Background sample holder for micro gram sample analysis should be offered having both cavity & flat surface.                        |  |
| 26.    |                              | Sample Holder for Spinner Sample Stage to hold Solid Flat<br>Samples and powder for<br>Reflection Geometry – Minimum 1 pcs                                 |  |

| 27.      | Sample holder for Coin Cell mounting along with 500 no's of Kapton films should be provided.  |  |
|----------|---|--|
| Detector |   |  |
| 28.      | High and A Call I Core 1D Detector  |  |
|          | High speed Solid State 1D Detector  |  |
| 29.      | Detector Should work in 0D,1D mode and also in scanning and static mode   |  |
| 30.      | Change 1- / Chaire / Director Minimum 125 No. 2 and 1-  |  |
| 31.      | Channels / Strips / Pixels : Minimum 125 No's or above  |  |
| 31.      | All Channels / strips/pixels should be active   |  |
| 32.      | 2 Stage PHD Based fluorescence reduction mode should be available.  |  |
| 33.      | Divad/Channel/Strip resolution of 100 micron or lawer   |  |
| 34.      | Pixcel/Channel/Strip resolution of 100 micron or lower.   |  |
| 34.      | Detector should not require any external cooling.   |  |
| G 0      |   |  |
| Software | Control monitoring data apprinting and approximately  |  |
| 35.      | Control, monitoring, data acquisition and processing software for the entire X-Ray Diffraction (XRD) system.                          |  |
| 36.      | for the churc A-Ray Diffraction (ARD) system.   |  |
| 50.      | Simultaneous measurement and analysis capability.   |  |
|          | The offered software should have facility to do background  |  |
|          | subtraction, smoothing, K α1 (K alpha 1), Kα2   |  |
|          | separation/elimination,   |  |
| 37.      | peak search and match, multiple peak separation, multiple   |  |
|          | plotting, custom report generation, peak or line profile analysis.  This shall include phase analysis (qualitative and quantitative), |  |
|          | crystallite size determination,   |  |
|          | % crystallinity, lattice strain determination,  |  |
|          | FWHM, particle size determination, 3D crystal structure display,  |  |
|          | indexing, lattice parameter calculation,  |  |
| 38.      | Rietveld refinement, standard less quantitative analysis,   |  |
|          | Reference Intensity Ration (RIR), Phase mapping etc.  |  |
|          | Software should be enabled with latest Rietveld algorithm for   |  |
|          | standard less quantitative analysis.  Facility for Automated Rietveld quantification set up of sample                                 |  |
| 39.      | should be available.  |  |
|          | The evaluation software should able to find peak position by  |  |
|          | five methods i.e. Gravity, Sliding Gravity, Parabolic,  |  |
|          | Pseudo-Voigt and Pearson VII. Also Calculation of the stress  |  |
|          | tensor in the sample and principal coordinates for normal,  |  |
| 40.      | normal & shear, biaxial, biaxial & shear, and triaxial stress   |  |
|          | models.   |  |
|          | Single License ICDD PDF2 data base suitable for Phase ID  |  |
| 41.      | Should be offered. ICDD database must be integrated into OEM analysis software's.   |  |
| 42       | COD database integrated into OEM software's with search   |  |
| 42.      | capability.   |  |
|          | Analysed data to be in standard formats as well as made   |  |
| 43.      | available in ASCII/CSV forms and  |  |
|          | exportable to popular platforms like MS Excel.  |  |
| 44.      | The Analysis software should be supplied with minimum 3 user  |  |
|          | license.  |  |

| 45.   |   |  |          |
|---|---|--|----------|
|   |   | Latest versions running on Windows 10 operating system (64-bit) or better.   |          |
| Comput  | ter   |  |          |
|   |   | One Internal/External PC for Instrument Control and  |          |
|   |   | additionally 1 or more External PC for data Analysis.  |          |
|   |   | The external PC should have the following minimum  |          |
|   |   | specification - Intel® Core i5,  |          |
|   |   | RAM: 16GB DDR3; HDD: 1TB; with Intel integrated Graphics   |          |
|   |   | card; DVD +/-RW;   |          |
| 46.   |   | Monitor: colour LED-23" size; OS: Windows-10 (64-bit) or   |          |
| 10.   |   | better licensed.   |          |
| Safety f  | eatures   |  |          |
|   |   | The system should be completely safe for x-ray radiations and  |          |
| 47.   |   | complies to all international safety norms for x-ray safety,   |          |
|   |   | electrical and mechanical safety   |          |
| 48.   |   | The maximum radiation output from the system at a distance of  |          |
| 701   |   | 10cms should be less than 1μS/hour.  |          |
| Power s   | upply   |  |          |
| 49.   |   | Single Phase, 200 to 230 V, 50/60 Hz   |          |
| Site Inst   | tallation   |  |          |
| 50.   | Site  |  |          |
| 30.   | Installation  | Site Installation should be done by factory trained engineer   |          |
| m · ·   |   |  | <u> </u> |
| Trainin   | <u>g</u>  | Negaciony training by a factory trained VDD Application  |          |
| 51.   | Training  | Necessary training by a factory trained XRD Application Specialist at site.  |          |
|   |   |  |          |
| Warran  | ıtv   |  |          |
| Warran<br>52.                                       | •   |  |          |
| Warran<br>52.                                       | <b>Warranty</b>   | 3 Year from the date of Installation of the BT XRD.  |          |
| 52.  Optiona  | Warranty al Items to be   |  |          |
| 52.  Optional quoted                                | Warranty  |  |          |
| 52.  Optiona  | Warranty al Items to be   |  |          |
| 52.  Optional quoted                                | Warranty al Items to be   | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  |          |
| 52.  Optiona quoted 53.  54.                        | Warranty  al Items to be with break up  | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers   |          |
| 52.  Optiona quoted 53.  54.                        | Warranty al Items to be   | A non-ambient heating stage with sample holder for Rt to +500  Deg in-situ temperature studies should be quoted.  Auto samplers  |          |
| 52.  Optiona quoted 53.  54.                        | Warranty  al Items to be with break up  | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers   |          |
| 52.  Optiona quoted 53.  54.                        | Warranty  Il Items to be with break up  and conditions  Manual                            | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers  Soft and hard copy of the manual should be provided with the instrument.   |          |
| 52.  Optiona quoted 53.  54.  Terms a 55.           | Warranty  Il Items to be with break up  and conditions  Manual  Test report               | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers  Soft and hard copy of the manual should be provided with the instrument.  Test report of the instrument should be provided.  |          |
| 52.  Optiona quoted 53.  54.  Terms a 55.  56.      | Warranty  Il Items to be with break up  and conditions  Manual                            | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers  Soft and hard copy of the manual should be provided with the instrument.  Test report of the instrument should be provided.  Installation should be free   |          |
| 52.  Optiona quoted 53.  54.  Terms a 55.  56.  57. | Warranty  Il Items to be with break up  and conditions  Manual  Test report               | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers  Soft and hard copy of the manual should be provided with the instrument.  Test report of the instrument should be provided.  Installation should be free  Training session related to equipment and software related to the  |          |
| 52.  Optiona quoted 53.  54.  Terms a 55.  56.      | Warranty  Il Items to be with break up  and conditions  Manual  Test report  Installation | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers  Soft and hard copy of the manual should be provided with the instrument.  Test report of the instrument should be provided.  Installation should be free  Training session related to equipment and software related to the system to be done atleast three times per year until warranty  |          |
| 52.  Optiona quoted 53.  54.  Terms a 55.  56.  57. | Warranty  Il Items to be with break up  and conditions  Manual  Test report               | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers  Soft and hard copy of the manual should be provided with the instrument.  Test report of the instrument should be provided.  Installation should be free  Training session related to equipment and software related to the system to be done atleast three times per year until warranty expire   |          |
| 52.  Optiona quoted 53.  54.  Terms a 55.  56.  57. | Warranty  Il Items to be with break up  and conditions  Manual  Test report  Installation | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers  Soft and hard copy of the manual should be provided with the instrument.  Test report of the instrument should be provided.  Installation should be free  Training session related to equipment and software related to the system to be done atleast three times per year until warranty expire  Minimum 3 years, Company must take responsibility to replace |          |
| 52.  Optiona quoted 53.  54.  Terms a 55.  56.  57. | Warranty  Il Items to be with break up  and conditions  Manual  Test report  Installation | A non-ambient heating stage with sample holder for Rt to +500 Deg in-situ temperature studies should be quoted.  Auto samplers  Soft and hard copy of the manual should be provided with the instrument.  Test report of the instrument should be provided.  Installation should be free  Training session related to equipment and software related to the system to be done atleast three times per year until warranty expire   |          |

| Service | Service facility and down-time call attendance |   |  |  |  |
|---------|--|---|--|--|--|
|         |  | Supplier should confirm the availability of spares for next 10 years from the date of installation. |  |  |  |
| 60.     |  | All essential spares for day-to-day operation needs should be                                       |  |  |  |
|         | Spares   | provided as standard supply.  |  |  |  |
|         | Pre-   |   |  |  |  |
| 61.     | Installation                                   | Necessary pre-installation advice should be sent immediately  |  |  |  |
|         | Requirement                                    | after the placement of the order.   |  |  |  |
| 62.     | Delivery                                       |   |  |  |  |
| 02.     | Condition                                      | The instrument should be delivered within 10-16 weeks.  |  |  |  |

(Note: It is mandatory for the bidders to provide the compliance statement in tabular column format along with catalogue page number (comply/not comply) for the Above points with document proof as required. Failing which bidders will be technically disqualified)